
| RESEARCH ARTICLE

AI-Driven Techniques for Power-Optimized and Safety-Critical SoC Design

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| ABSTRACT

Artificial intelligence is transforming System-on-Chip design, particularly for applications requiring both power efficiency and functional safety. Traditional methodologies face mounting challenges as SoC complexity increases, creating an urgent need for innovative approaches that can navigate extensive design spaces while maintaining safety guarantees. Machine learning techniques throughout the design flow—from architecture exploration to verification—enable sophisticated power optimization without compromising reliability requirements. Deep reinforcement learning optimizes floorplanning while neural networks predict congestion and timing issues early in the process. AI-driven power domain partitioning and dynamic voltage/frequency scaling provide unprecedented control over energy consumption. For safety-critical applications, these techniques incorporate specialized constraints, ensuring fault tolerance while minimizing power overhead. Despite significant advancements, challenges remain in explainability and certification integration, areas where ongoing development continues to bridge the gap between AI-enhanced optimization and safety compliance requirements.

| KEYWORDS

Power Optimization, Safety-critical Systems, Machine Learning, System-on-chip Design, Verification Methodology.

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1. Introduction

Artificial intelligence techniques are rapidly transforming System-on-Chip (SoC) design flows, particularly in power optimization and safety-critical applications. The increasing complexity of modern SoC architectures has pushed traditional design methodologies to their limits, creating significant challenges in balancing stringent power budgets with functional safety requirements. The semiconductor industry faces mounting pressure to deliver more capable chips with lower power consumption while ensuring reliability for critical systems in the automotive, medical, and aerospace domains [1]. This complexity explosion necessitates new approaches that can navigate vast design spaces efficiently while maintaining safety guarantees.

AI-driven methodologies offer compelling solutions by automating complex design decisions, providing early predictions of design outcomes, and optimizing across multiple competing objectives simultaneously. Machine learning algorithms applied to electronic design automation (EDA) workflows have demonstrated remarkable capabilities in accelerating design cycles while improving quality metrics. These techniques span the entire SoC development process, from architectural exploration to physical implementation and verification [1]. The application of reinforcement learning algorithms to chip design tasks represents a fundamental shift in how complex tradeoffs between performance, power, and area are managed, enabling more holistic optimization than traditional compartmentalized approaches permit.

For power-constrained safety-critical systems, AI-based techniques provide unprecedented capabilities to model and optimize dynamic behavior under varying operational conditions. Advanced machine learning models can capture complex relationships between architectural choices and resulting power profiles, enabling more sophisticated power gating strategies and dynamic

voltage/frequency scaling implementations. These techniques help designers identify optimal power domain partitioning and develop robust power management schemes that maintain safety margins while maximizing energy efficiency [2]. Safety-critical systems particularly benefit from this approach, as power-related failures can compromise functional safety in applications where reliability is paramount.

In the physical implementation domain, neural network-based prediction models offer early insights into potential power, performance, and area outcomes before completing time-consuming implementation steps. This predictive capability enables designers to make informed architectural decisions earlier in the design process, avoiding costly iterations when power issues are discovered late in the development cycle [2]. The ability to forecast congestion hotspots, timing problems, and power distribution challenges before detailed implementation provides valuable guidance for safety-critical block placement and routing strategies.

Verification of safety-critical SoCs has also been enhanced through AI integration, with machine learning models improving test coverage while reducing verification time. Power-related functional issues, which often manifest only under specific operating conditions, can be more effectively identified through intelligent test generation guided by learning algorithms. For safety-critical applications requiring certification, AI-assisted verification methodologies help achieve comprehensive coverage of power-related failure modes while providing the necessary evidence for safety case development [1]. This comprehensive approach to power-aware verification is essential for safety-critical systems where undetected power issues could lead to catastrophic failures.

The integration of these AI techniques throughout the SoC design flow is creating new possibilities for architectural innovations in power-optimized safety-critical systems. Design teams can now explore more configuration options and implement sophisticated power management schemes that would have been impractical using traditional methodologies [2]. However, important challenges remain in establishing trust in AI-enhanced design flows, particularly for certification processes that demand high levels of determinism and explainability. The semiconductor industry continues to refine these approaches, developing frameworks that combine the benefits of AI optimization with the rigor required for safety-critical system development.

2. AI-Powered Design Space Exploration for Power-Optimized SoC Architectures

The complexity of modern System-on-Chip (SoC) architectures creates a vast design space that traditional methodologies struggle to explore effectively. AI-powered design space exploration (DSE) techniques have emerged as powerful tools for navigating the multitude of possible configurations while optimizing for power efficiency in safety-critical applications. Multi-objective optimization techniques, including Bayesian optimization, genetic algorithms, and reinforcement learning, enable designers to balance competing objectives such as performance, power consumption, and safety requirements. These approaches identify Pareto-optimal solutions that represent the best possible trade-offs between competing metrics without requiring exhaustive evaluation of every potential design point [3]. For safety-critical systems, these techniques incorporate additional constraints that ensure functional safety requirements are maintained while power optimization occurs, addressing the growing need for energy-efficient yet reliable SoC architectures.

Power-aware architecture search frameworks for SoC components leverage AI techniques to explore specialized accelerator designs, processor configurations, and memory hierarchies. Recent research has focused on developing efficient exploration methodologies for convolutional neural network accelerators targeting edge devices where power constraints are particularly stringent. These frameworks employ multi-level modeling approaches that combine analytical models with machine learning techniques to predict performance and energy consumption across various hardware configurations. The approach enables rapid evaluation of different dataflow architectures, memory sizing options, and processing element arrangements without requiring full implementation for each design variant [3]. When applied to safety-critical applications such as automotive vision processing or medical monitoring systems, these frameworks incorporate additional parameters related to fault tolerance and error detection capabilities, ensuring that power optimization does not compromise essential safety features.

Automated power domain partitioning and power gating strategies represent a critical aspect of power-optimized SoC design that has benefited significantly from AI assistance. Machine learning algorithms analyze functional dependencies and activity patterns across diverse workloads to identify optimal power domain boundaries. This analysis considers both static leakage reduction opportunities and dynamic switching characteristics, resulting in power domain configurations that maximize energy savings while maintaining system functionality. For safety-critical applications, these algorithms incorporate additional constraints related to isolation requirements and fault containment regions, ensuring that power domain partitioning aligns with safety certification requirements [4]. The resulting architectures feature sophisticated power gating strategies that selectively

deactivate non-critical components while maintaining continuous operation of safety-critical functions, addressing the challenges of mixed-criticality systems.

Recent advancements in AI-driven DSE have produced impressive power-performance-area (PPA) improvements in power-constrained designs across various application domains. These case studies demonstrate how intelligent exploration of the design space can identify non-intuitive architectural configurations that traditional methodologies might overlook. For example, research on vision-based autonomous systems has shown how neural architecture search techniques can be combined with hardware-aware optimization to develop specialized accelerators that meet strict power budgets while maintaining real-time performance requirements [3]. Similar approaches applied to industrial control and medical monitoring SoCs have demonstrated the ability to reduce power consumption while maintaining or improving reliability metrics, addressing the growing demand for energy-efficient safety-critical systems in resource-constrained environments.

Safety considerations introduce unique challenges to architecture exploration for critical systems, requiring specialized AI techniques that incorporate formal verification and reliability analysis. Modern DSE frameworks incorporate safety metrics directly into the optimization process, ensuring that architectural decisions maintain required safety integrity levels while pursuing power efficiency goals. Recent research has focused on developing safety-aware optimization techniques that explicitly model the impact of various fault tolerance mechanisms on both reliability and power consumption [4]. These approaches enable the exploration of novel architectural patterns that move beyond traditional redundancy schemes, identifying configurations that provide equivalent or superior safety guarantees with lower power overhead. For example, selective hardening techniques guided by AI-based criticality analysis can focus reliability enhancement measures on the most vulnerable system components, reducing the power penalties associated with comprehensive redundancy approaches. This safety-aware exploration becomes increasingly important as SoCs integrate more heterogeneous components with varying criticality levels, allowing for fine-grained optimization of power-safety trade-offs.

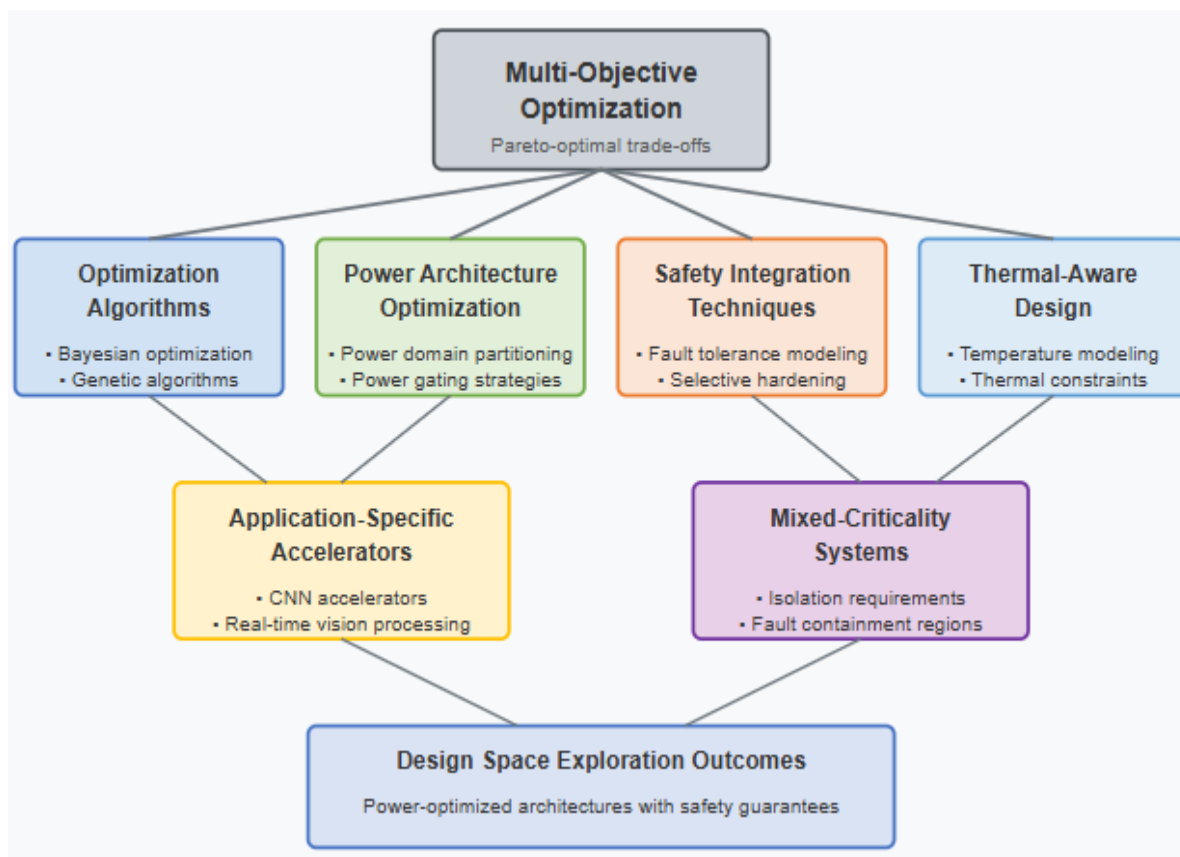


Fig 1: AI-Powered Design Space Exploration [3, 4]

The integration of power and thermal awareness into safety-critical system exploration represents another frontier in AI-assisted SoC design. Advanced DSE frameworks now incorporate detailed power and thermal modeling to identify configurations that remain within safe operating limits across all anticipated operating conditions. This approach is particularly important for systems where thermal management directly impacts both reliability and functional safety [4]. By exploring the relationship

between architectural decisions, power profiles, and resulting thermal characteristics, these frameworks help designers develop SoCs that maintain safe operating temperatures without requiring overly conservative design margins or excessive cooling infrastructure. The resulting architectures feature sophisticated power management schemes that adapt to changing thermal conditions while preserving essential safety functions, addressing the challenges of deploying safety-critical systems in harsh environmental conditions.

3. Machine Learning for Power Estimation and Optimization

The integration of machine learning techniques into power estimation workflows has transformed how designers approach power analysis throughout the SoC development cycle. Dynamic power estimation using ML models trained on simulation activity data enables accurate power predictions much earlier in the design process, providing valuable insights before detailed implementation. Traditional approaches rely on gate-level simulation with complete switching activity information, creating a significant bottleneck as these simulations become available only after substantial implementation work. ML-based methodologies learn the relationship between higher-level design representations and resulting power consumption patterns [5]. These techniques employ neural network architectures trained on datasets that pair design parameters and workload characteristics with corresponding power measurements. This capability is particularly valuable for safety-critical applications, enabling thorough exploration of power profiles across diverse operational scenarios, including fault conditions.

Early-stage leakage power prediction has become increasingly important as static power consumption represents a growing proportion of the overall power budget in advanced technology nodes. Machine learning approaches analyze the complex relationships between process parameters, cell types, and resulting leakage currents. These techniques have proven especially valuable for modeling the effects of process variations on leakage power, capturing statistical distributions rather than just nominal values [5]. For safety-critical applications, accurate leakage prediction becomes particularly important when designing power management strategies for long-term standby modes where static power dominates, ensuring that battery backup systems and power monitoring circuits are dimensioned appropriately.

Activity-based power domain partitioning represents a complex optimization problem well-suited to AI-guided approaches. Machine learning techniques process data from system-level simulations across representative workloads to discover natural boundaries for power domains based on actual usage patterns rather than just architectural hierarchy [6]. For safety-critical systems, the power domain partitioning must also respect isolation requirements between components of different criticality levels. ML algorithms address this challenge by incorporating safety constraints directly into the domain identification process, ensuring that the resulting power architecture maintains appropriate isolation while maximizing power-saving opportunities.

ML-driven Dynamic Voltage and Frequency Scaling (DVFS) optimization has evolved significantly, moving beyond simple workload-based approaches to sophisticated predictive control strategies. Modern DVFS controllers use machine learning to predict future computational demands, enabling proactive adjustment of voltage and frequency settings before workload changes occur [6]. For safety-critical applications, these controllers incorporate additional constraints related to worst-case execution time guarantees and minimum performance requirements for critical tasks, providing more nuanced power management than traditional approaches.

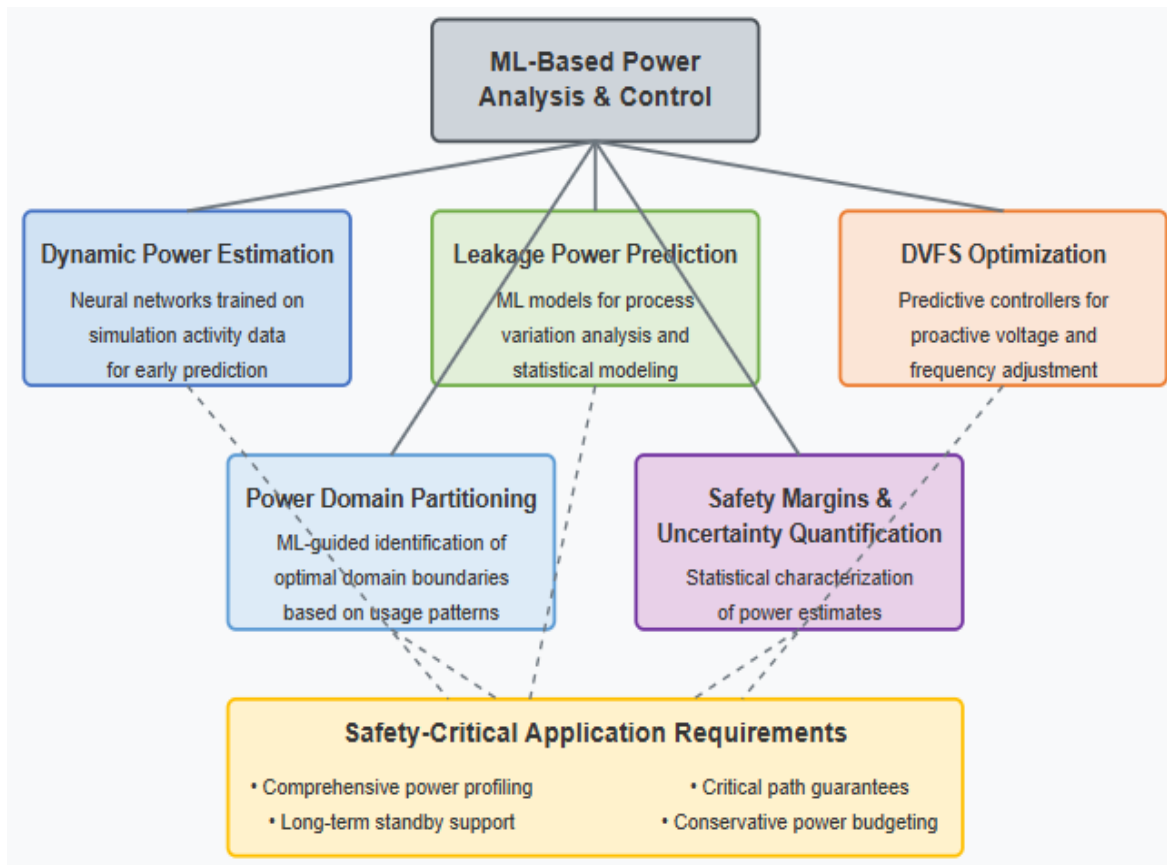


Fig 2: Machine Learning for Power Estimation and Optimization [5, 6]

Safety margins and uncertainty quantification have become essential considerations as ML-based power estimation techniques gain adoption in critical applications. Specialized ML architectures provide not just point estimates but comprehensive statistical characterizations of predicted power consumption [5]. This capability is particularly important for safety-critical applications where conservative power budgeting is essential, allowing designers to make informed decisions about how much margin to add based on quantified uncertainty rather than arbitrary safety factors.

3. AI-Enhanced Physical Implementation for Low-Power SoCs

The physical implementation stage of SoC design has undergone a remarkable transformation through the integration of artificial intelligence techniques, particularly in addressing the complex challenges of power-efficient design. Deep reinforcement learning (DRL) for power-efficient floorplanning represents one of the most significant breakthroughs in this domain, offering a fundamentally new approach to the placement of macros and IP blocks. DRL frameworks formulate the floorplanning problem as a sequential decision-making process where an agent learns to optimize block placement by interacting with the design environment [7]. This method has proven particularly effective for safety-critical SoCs where power integrity must be maintained across all operating conditions while ensuring critical blocks receive adequate power delivery resources and maintaining appropriate physical separation between redundant components to prevent common-mode failures.

Congestion and timing prediction models have emerged as essential tools for early design guidance, enabling designers to anticipate implementation challenges before committing to detailed place and route. Machine learning approaches to congestion prediction typically employ graph neural networks or convolutional neural networks that analyze netlist connectivity patterns and placement densities to identify potential hotspots [7]. For power-optimized safety-critical designs, these prediction capabilities enable more effective planning of redundant circuits and isolation zones, ensuring that fault containment regions can be successfully implemented without creating intractable routing problems.

Power-aware clock tree synthesis (CTS) optimization has benefited significantly from machine learning techniques that balance multiple competing objectives, including power consumption, skew minimization, and reliability enhancement. ML-enhanced CTS optimization frameworks learn from extensive design data to identify clock tree topologies and buffer insertion strategies that minimize power consumption while maintaining strict skew requirements [8]. For safety-critical applications, the ML-driven

optimization additionally addresses reliability concerns by ensuring appropriate buffer sizing margins, implementing balanced tree structures, and strategically placing clock buffers to minimize susceptibility to common-mode failures.

Automated Engineering Change Order (ECO) generation for timing and power optimization employs machine learning to analyze design characteristics, timing reports, and power profiles, automatically identifying appropriate modifications with minimal disruption [8]. For safety-critical applications, these systems incorporate additional verification steps to ensure that proposed modifications maintain required safety properties, including fault detection coverage and redundancy effectiveness.

ML-driven multi-threshold voltage (multi-Vt) cell optimization analyzes the intricate interactions between cell placement, timing paths, switching activity, and resulting leakage characteristics to identify optimal Vt assignments across the design [7]. For safety-critical applications, this optimization incorporates additional considerations related to reliability and aging effects, ensuring that critical paths maintain appropriate timing margins throughout the device's lifetime.

Physical implementation considerations for safety-critical circuit redundancy benefit from machine learning techniques that analyze potential common-mode failure mechanisms and optimize placement to enhance fault isolation capabilities [8]. These approaches balance maintaining appropriate separation between redundant elements while optimizing for overall power efficiency and routing congestion, enabling sophisticated fault tolerance strategies while maintaining power optimization objectives.

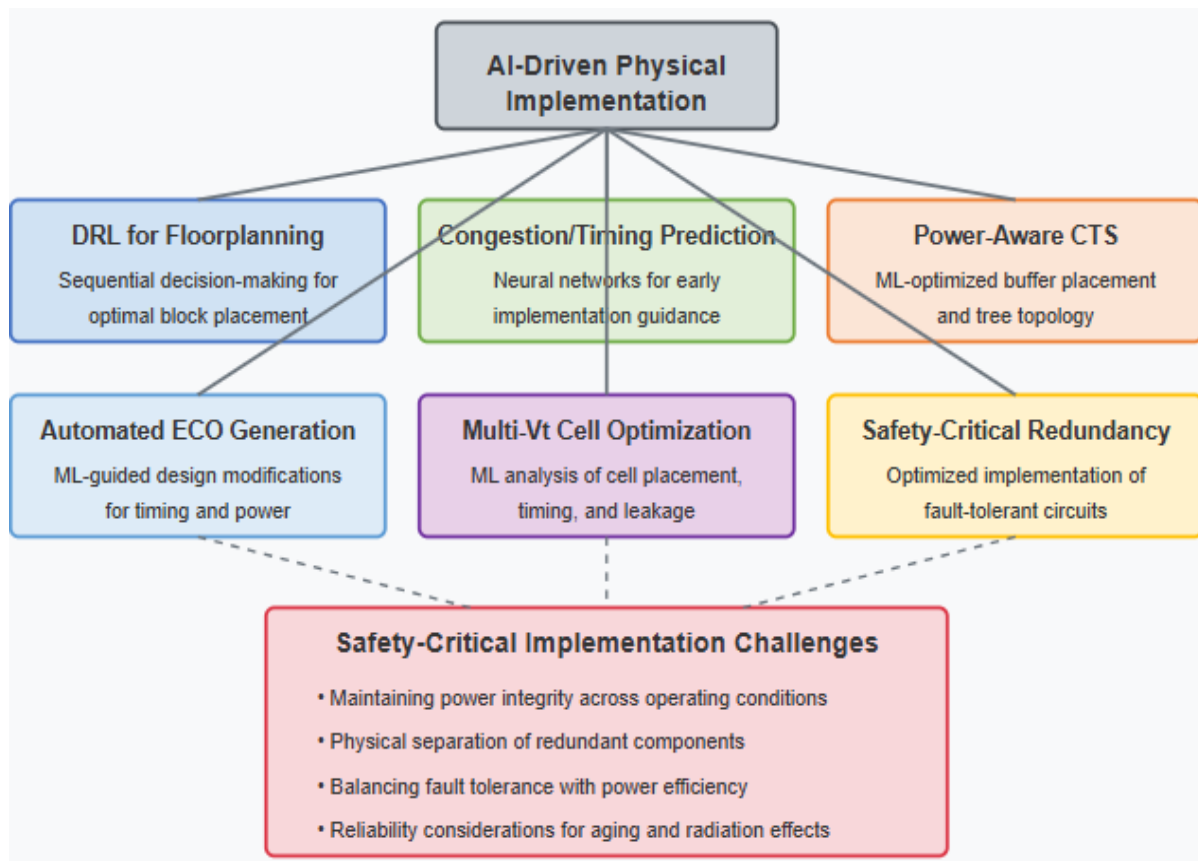


Fig 3: AI-Enhanced Physical Implementation for Low-Power SoCs [7, 8]

4. Verification and Validation of AI-optimized safety-critical SoCs

The verification and validation of AI-optimized safety-critical SoCs present unique challenges that require innovative methodologies to ensure functional correctness and reliability. AI-assisted test pattern generation has emerged as a powerful approach for achieving comprehensive fault coverage while managing the exponential growth in verification complexity. Machine learning techniques enhance ATPG by analyzing design structures and historical test data to identify patterns that more effectively target difficult-to-detect faults, especially those related to power distribution networks and clock domains [9]. These approaches have proven especially valuable for safety-critical applications where comprehensive fault coverage must be demonstrated as part of the certification process, particularly for power-related failure modes that might only manifest under specific voltage, frequency, and temperature conditions.

Machine learning for adaptive test strategies has transformed how safety-critical systems are validated throughout their lifecycle. ML-driven adaptive test methodologies continuously analyze test responses and operational data to identify potential reliability issues before they manifest as functional failures [9]. The adaptive test strategies become particularly valuable for safety-critical applications where continuous operation must be maintained despite potential hardware degradation. The ML models analyze parameters such as voltage margins, timing characteristics, and power consumption patterns to identify subtle shifts that might indicate developing reliability issues, triggering appropriate containment or recovery actions.

Bug prediction and triage focused on power-related functional issues address verification challenges where traditional coverage metrics often fail to adequately capture complex power-dependent behaviors. Machine learning approaches analyze design attributes, verification metrics, and historical defect data to identify design regions with elevated risk of power-related failures [10]. For safety-critical applications, these approaches prioritize issues that could impact essential functions or compromise isolation between components of different criticality levels, enabling verification teams to focus limited resources on the most critical concerns.

Intelligent coverage closure for safety-critical design aspects transforms how verification completeness is measured and achieved. Machine learning techniques analyze the relationship between various coverage metrics and actual defect detection rates, identifying the most valuable coverage goals and revealing gaps in verification plans [10]. These approaches help verification teams identify untested combinations of power states and functional operations that might contain latent defects, providing more comprehensive evidence of verification completeness for safety certification.

Verification of AI-optimized power management systems combines formal methods with advanced simulation techniques to validate the behavior of adaptive systems under both nominal and extreme conditions [9]. These methodologies address the fundamental challenge of validating non-deterministic components within systems requiring deterministic safety guarantees, enabling the adoption of advanced power optimization techniques while maintaining compliance with functional safety standards.

Certification considerations for AI-enhanced safety-critical SoCs focus on establishing clear boundaries for ML-based components, implementing runtime monitoring, and providing fallback mechanisms [10]. This layered approach enables the adoption of power-efficient AI techniques while maintaining the rigorous safety standards required for critical applications, addressing the growing demand for sophisticated power management without compromising certification requirements.

Area	AI/ML Role	Key Benefit
Test Pattern Generation	ML-enhanced ATPG	Better fault coverage
Adaptive Testing	ML analyzes test data	Detects early hardware issues
Bug Prediction	ML identifies high-risk zones	Prioritized verification
Coverage Closure	ML links coverage to defect detection	Finds critical coverage gaps
Power Management Verification	Formal + simulation methods	Validates under extreme conditions
Certification Support	Runtime monitoring & fallback via ML	Meets safety standards with AI efficiency

Table 1: AI Techniques in Safety-Critical SoC Verification [9, 10]

5. Conclusion

AI-driven techniques have revolutionized SoC design by enabling sophisticated power optimization while maintaining reliability for safety-critical applications. These approaches provide designers with powerful tools to navigate complex trade-offs between performance, power efficiency, area utilization, and functional safety. As these technologies mature, adoption continues to expand across the semiconductor industry, particularly in domains where both power constraints and safety considerations are paramount. Significant challenges exist in explainability, verification of AI-enhanced designs, and integration with formal certification processes. Future directions should address these challenges while expanding the capabilities and accessibility of AI-driven design methodologies for power-optimized, safety-critical SoC development, ultimately creating more efficient yet safer electronic systems for automotive, medical, aerospace, and industrial applications.

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References

- [1] Azalia M et al. (2020). Chip Placement with Deep Reinforcement Learning, arXiv:2004.10746v1. [Online]. Available: <https://arxiv.org/pdf/2004.10746>
- [2] Dan Y et al. (n.d). A Survey of Machine Learning Applications in Functional Verification. [Online]. Available: <https://dvcon-proceedings.org/wp-content/uploads/1135-A-Survey-of-Machine-Learning-Applications-in-Functional-Verification.pdf>
- [3] Foivos T et al. (2028). A Design Space Exploration Framework for Convolutional Neural Networks Implemented on Edge Devices, ResearchGate, 2018. [Online]. Available: https://www.researchgate.net/publication/326485881_A_Design_Space_Exploration_Framework_for_Convolutional_Neural_Networks_Implemented_on_Edge_Devices
- [4] Guyue H et al. (2021). Machine Learning for Electronic Design Automation: A Survey, arXiv:2102.03357, 2021. [Online]. Available: <https://arxiv.org/abs/2102.03357>
- [5] Guyue H et al. (2021). Machine Learning for Electronic Design Automation: A Survey, arXiv:2102.03357v2, 2021. [Online]. Available: <https://arxiv.org/pdf/2102.03357>
- [6] Ke H et al. (2013). Counterfeit Electronics: A Rising Threat in the Semiconductor Manufacturing Industry, IEEE, 2013. [Online]. Available: https://perso.univ-st-etienne.fr/bl16388h/salware/Bibliography_Salware/IC%20Counterfeiting/Article/Huang2013.pdf
- [7] Kevin I G et al. (2022). Survey of Machine Learning for Electronic Design Automation, ACM, 2022. [Online]. Available: <https://dl.acm.org/doi/pdf/10.1145/3526241.3530834>
- [8] Loïc M et al. (2019). A Comprehensive Study of Deep Learning for Side-Channel Analysis, RUB, 2019. [Online]. Available: <https://metalla.org/index.php/TCHES/article/view/8402>
- [9] Pingakshya G et al. (2023). Application of Machine Learning in FPGA EDA Tool Development, IEEE Access. [Online]. Available: <https://ieeexplore.ieee.org/stamp/stamp.jsp?arnumber=10272331>
- [10] Vinay P, (2024). Mobile SoC Power Optimization: Redefining Performance with Machine Learning Techniques, IJRSET. [Online]. Available: https://www.ijrset.com/upload/2024/december/117_Mobile.pdf